Se	arcn Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/510,195	CHEN ET AL.	
Examiner	Art Unit	
Benjamin Kurtz	1797	

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Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner

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SEARCH NOT (INCLUDING SEARCH	'ES STRATEGY))
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Inventor name and EAST search	1/18/2008	вк
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